EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L7	2	(VARSHNEY.in. or CHANDRASEKAR.in.) and glitch	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:12
L8	38	(VARSHNEY.in. or CHANDRASEKAR.in.) and noise	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:12
L9	2	(VARSHNEY.in. or CHANDRASEKAR.in.) and (noise with immunity)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:13
L10	684	glitch and (noise with immunity)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:56
L11	151	((worst or pessimistic) with bit) and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:51
L12	246	(curve or plot or graph) with (failure or fail$3 or fall$3) with (glitch or noise)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:26
L13	5	(curve or plot or graph) with (failure or fail$3 or fall$3) with (glitch or noise) with immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:46
L14	1	11 and 13	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:45
L15	6	(curve or plot or graph) with (failure or fail$3 or fall$3) with (glitch or noise) same immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:53
L16	15	(curve or plot or graph) with (failure or fail$3 or fall$3) with (glitch or noise) and immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:50
L17	18	(curve or plot or graph) same (failure or fail$3 or fall$3) same (glitch or noise) same immunity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:51

L18	1	17 and 11	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:51
L19	159	((worst or pessimistic) same bit) and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L20	1	17 and 19	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L21	263	((worst or pessimistic) and bit) and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L22	1	17 and 21	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 14:52
L23	4	((curve or plot or graph) and (failure or fail$3 or fall$3) and (glitch or noise) and immunity).clm.	US-PGPUB	OR	ON	2007/07/05 14:54
L24	1	((worst or pessimistic) and bit).clm. and 23	US-PGPUB	OR	ON	2007/07/05 14:55
L25	1	(worst or pessimistic).clm. and 23	US-PGPUB	OR	ON	2007/07/05 14:57
L26	1	bit.clm. and 23	US-PGPUB	OR	ON	2007/07/05 14:55
L27	4	(glitch and noise and immunity).clm.	US-PGPUB	OR	ON	2007/07/05 14:57
L28	1	(worst or pessimistic).clm. and 27	US-PGPUB	OR	ON	2007/07/05 14:58
L29	3	23 and 27	US-PGPUB	OR	ON	2007/07/05 14:57
L30	1	(worst or pessimistic).clm. and 29	US-PGPUB	OR	ON	2007/07/05 14:58
L31	2	("6836873").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2007/07/05 15:21
L32	0	("7760498").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2007/07/05 15:27
L33	2843	716/4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 15:53
L34	2164	716/5.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 16:26

L35	1747	716/6.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 17:06
L36	1239	703/14.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/05 17:06

IEEE *Xplore*®
RELEASE 2.3

Welcome United States Patent and Trademark Office

Search Results   BROWSE   SEARCH   IEEE XPLORE GUIDE

Results for "((immunity and noise and glitch and (worst or pessimistic))<in>metadata)"   ✉e-mail
Your search matched 1 of **1597822** documents.
A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» Search Options

View Session History   **Modify Search**

New Search   ((immunity and noise and glitch and (worst or pessimistic))<in>metadata)   ▸Search▸▸

                    ☐ Check to search only within this results set

» Key   Display Format: ⦿ Citation   ◯ Citation & Abstract

IEEE JNL   IEEE Journal or Magazine

IET JNL   IET Journal or Magazine   ⌐ view selected items]   **Select All Deselect All**

IEEE CNF   IEEE Conference Proceeding

IET CNF   IET Conference Proceeding   ☐   1. **Aggressor aware repeater circuits for improving on-chip bus performance and robustness**
                                                           Katoch, A.; Jain, S.K.; Meijer, M.;
IEEE STD   IEEE Standard   Solid-State Circuits Conference, 2003. ESSCIRC '03. Proceedings of the 29th European
                                                           16-18 Sept. 2003 Page(s):261 - 264
                                                           Digital Object Identifier 10.1109/ESSCIRC.2003.1257122

                                                           AbstractPlus | Full Text: PDF(518 KB)   IEEE CNF
                                                           Rights and Permissions

Indexed by
畐 Inspec®

IEEE *Xplore* ®
RELEASE 2.3

Welcome United States Patent and Trademark Office

☐☐Advanced Search

BROWSE   SEARCH   IEEE XPLORE GUIDE

OPTION 1
Enter keywords or phrases, select fields, and select operators

? Help

| | in All Fields | ↕ |

AND ▾ | | in All Fields | ↕ |

AND ▾ | | in All Fields | ↕ |

» Note: If you use all three search boxes, the entries in the first two boxes take precedence over the entry in the third box.

OPTION 2
Enter keywords, phrases, or a Boolean expression

? Help

```
immunity and noise and glitch and (worst
or pessimistic)
```

» Note: You may use the search operators <and> or <or>
without the start and end brackets <>.

» Learn more about Field Codes, Search Examples, and Search Operators

» **Publications**

  ◉ Select publications

    ☑ IEEE Periodicals

    ☑ IET Periodicals

    ☑ IEEE Conference Proce

    ☑ IET Conference Procee

    ☑ IEEE Standards

» **Other Resources** (Available for P

    ☑ IEEE Books

» **Standard Status**
  (Applies to IEEE Standards only)

    Status | All ▾ |

» **Select date range**

  ○ Search latest content update

  ◉ From year | All ▾ |

              to | Present ▾ |

» **Display Format**

  ◉ Citation   ○ Citation

» **Organize results**

    Maximum | 100 ▾ |

    Display | 25 ▾ | resul

    Sort by | Relevance ▾ |

        In | Descending ▾ |

Help   Contac

© Cop∖

Indexed by
☵ Inspec®